Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10702449	MORISHITA, TAKUYA
Examiner	Art Unit
Werner, David N	2621

SEARCHED							
Class	Subclass	Date	Examiner				
386	52, 53, 98	5/29/2007	DNW				
375	240.13	5/30/2007	DNW				
386	55	6/1/2007	DNW				
386	52, 53	10/31/2007	DNW				

SEARCH NOTES				
Search Notes	Date	Examiner		
EAST	5/29/2007	DNW		
Esp@cenet	5/29/2007	DNW		
E-mail to Thai Tran regarding allowability	6/1/2007	DNW		
Double-Patent check	6/4/2007	DNW		
EAST	10/31/2007	DNW		
Espacenet	11/1/2007	DNW		
Espacenet, ISR for W0 01/35411 A1 (same as cited Lin et al. reference)	5/5/2008	DNW		
searched				
IEEE Xplore	5/5/2008	DNW		

	INTERFERENCE SEA	INTERFERENCE SEARCH		
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